**Tytuł prezentacji: "Recent advances in Atom Probe Tomography (APT)".**

**Streszczenie:**Recent advances in Atom Probe Tomography (APT) technology and related improvement in analytical capability.

A number of innovations in Atom Probe instrument design have recently become available, which have had a significant impact on the range and types of materials that can be studied.  These changes include full cryo-specimen preparation and transfer, the adoption of shorter wavelength (DUV) laser pulsing, larger solid angle detection systems for increased field of view, and the introduction of a new voltage plus laser pulsed data acquisition mode. Each of these developments will be introduced and the examples of the benefits will be shown and discussed.

***Peter H. Clifton, PhD*** *– Specjalista w dziedzinie APT w firmie Cameca.*

*Posiada stopień naukowy z fizyki i doktorat z fizyki ciała stałego.*

*Może pochwalić się prawie 25 – letnim doświadczeniem w technice APT (w tym w wykorzystywaniu APT w badaniach akademickich, jak i komercyjnych).*